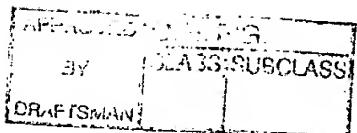


Title: IMPROVING SEM INSPECTION AND ANALYSIS OF PATTERNED PHOTORESIST FEATURES

Inventor(s): Uzodinma Okoroanyanwu et al.

Appl. NO.: 09 / 820, 143



1 / 4

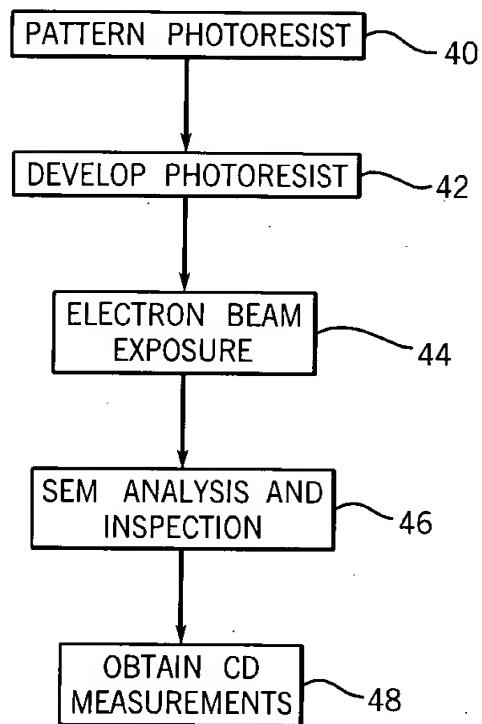
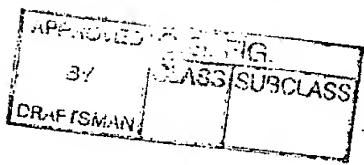


FIG. 1



2 / 4

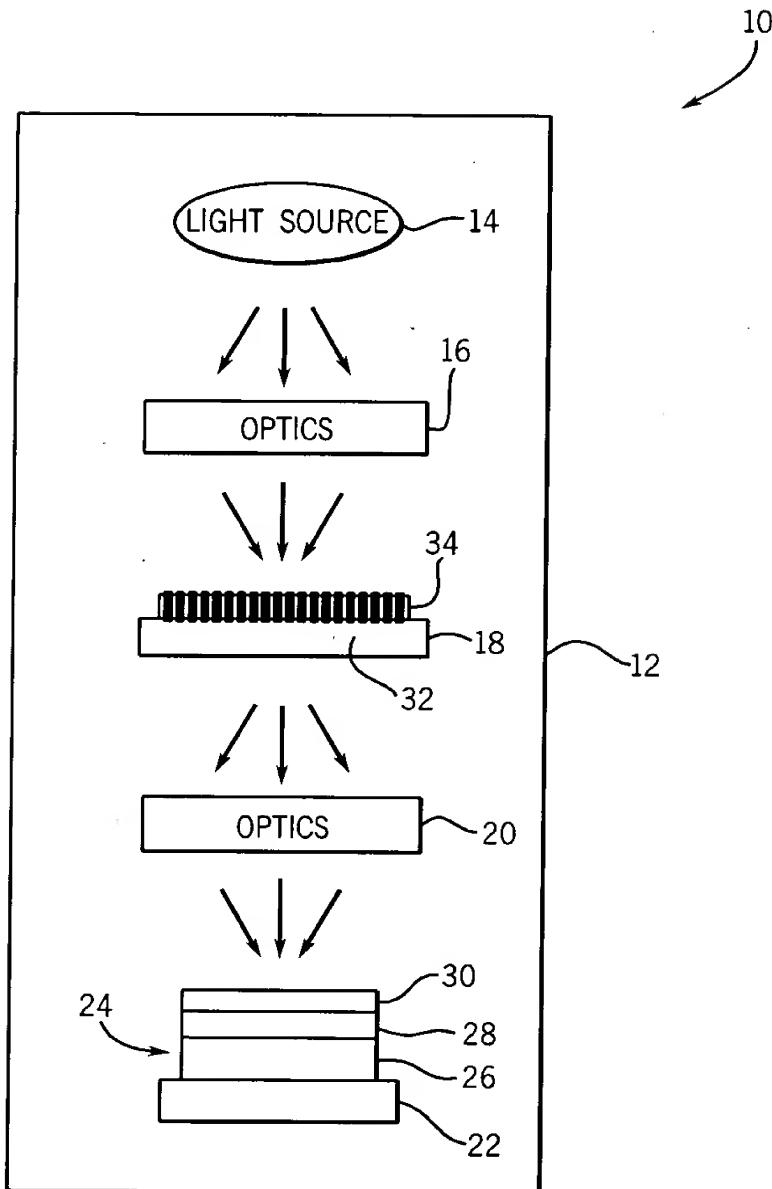


FIG. 2

APPLICANT'S NAME, FIRM	CLASG SUBCLASS
BY	
DRAFTER	

3 / 4

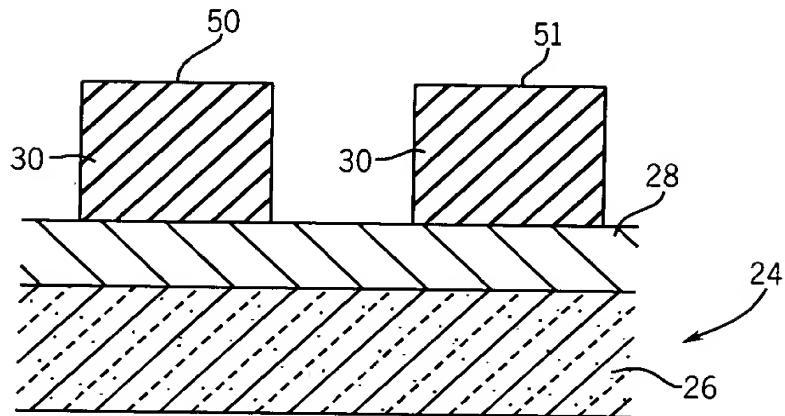


FIG. 3

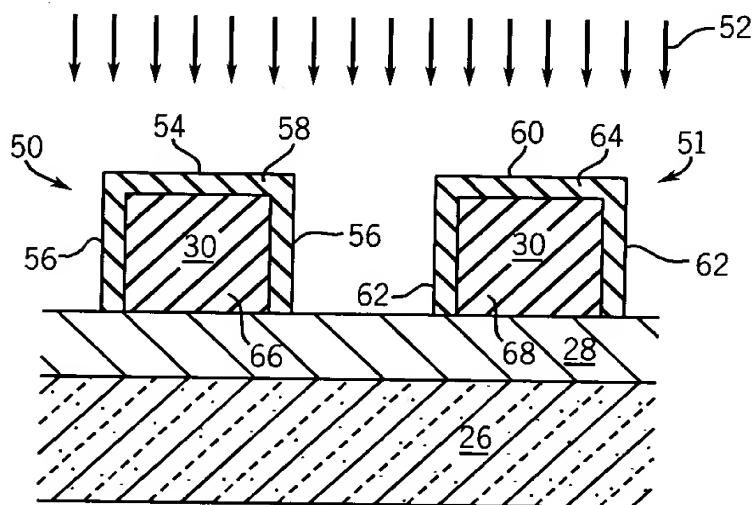


FIG. 4

APPROVED BY: D.G. FIG. 5
CLASS: 117 SUBCLASS:
DRAFTSMAN:

4 / 4

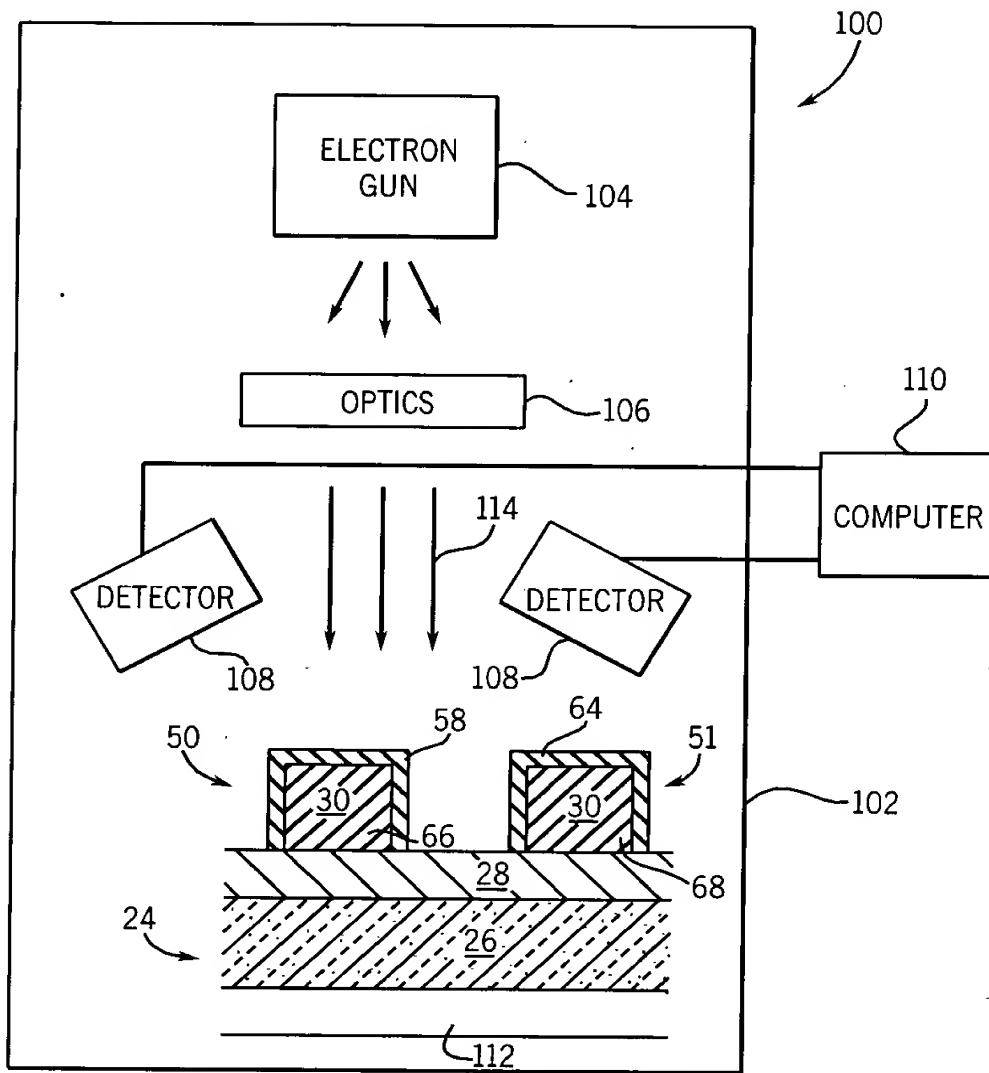


FIG. 5